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SJ

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Integrated circuits latch-up test

集成电路锁定试验

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What this standard covers

This standard specifies the integrated circuit (IC) of the current lockout and overvoltage lockout of test methods. This standard applies to create a test IC lock test method used to determine the IC locking feature and make sure the lock failure criterion. Lock sensitivity for determining product reliability, minimum no failure rate (NTF) and over electrical stress failure (EOS) is very important. This test method is applicable to NMOS, CMOS, bipolar and a variety of products using such processes. When the device is placed in the test method appears locked, indicating failure of the electrical properties of the device, independent of the special structure of the device.

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